Notice of References Cited Application/Control No. 10/736,055 Examiner JASON K. LIN Applicant(s)/Patent Under Reexamination ABIEZZI ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0126600	07-2003	Heuvelman, Jeroen	725/35
*	В	US-7,305,694	12-2007	Commons et al.	725/80
*	C	US-7,451,281	11-2008	Hanks, D. Mitchel	711/154
*	D	US-2002/0129374	09-2002	FREEMAN et al.	725/91
*	Е	US-2002/0088011	07-2002	Lamkin et al.	725/142
*	F	US-2003/0204852	10-2003	FENWICK et al.	725/83
*	G	US-2003/0135860	07-2003	Dureau, Vincent	725/82
*	Η	US-5,563,661	10-1996	Takahashi et al.	348/390.1
*	I	US-6,154,206	11-2000	Ludtke, Harold Aaron	713/168
*	J	US-6,363,434	03-2002	Eytchison, Edward Blaine	719/313
*	К	US-6,732,373	05-2004	Harrison et al.	725/141
*	L	US-2003/0028892	02-2003	Gewickey et al.	725/110
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	C						
	>						
	w						
	х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.